

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10766869	UMEZAWA ET AL.
	Examiner	Art Unit
	Paliwal, Yogesh	2135

SEARCHED

Class	Subclass	Date	Examiner
713	155,156	11/13/2007	YP

SEARCH NOTES

Search Notes	Date	Examiner
Inventor name search in east+Google+IEEE	5/23/2007	YP
(713/156-158) + Keywords -See search history printout	5/24/2007	YP
(713.CLAS) + Keywords - See search history printout	5/24/2007	YP
(726/9) + Keywords - See search history printout	5/24/2007	YP
(713/175) + Keyword - See search history printout	5/24/2007	YP
(705/65-69) + Keyword - See search history printout	5/24/2007	YP
(713/172-174) + Keyword -See search history printout	5/24/2007	YP
(726/10) + Keyword -See search history printout	5/24/2007	YP
NPL search (Done by STIC)	3/14/2007	YP
Database search - IEEE - See search history printout	5/24/2007	YP
Database search - Dialog - See search history printout	5/24/2007	YP
Consulted with Ponnoreay Pich (AU 2135)	11/7/2007	YP
Fast & Focused search (Foreign databases + NPL, Done by EIC 2100 Staff)	11/8/2007	YP
(713/155,156,157,158,168,175,172,173,174) + Keywords - See search history printout	11/13/2007	YP
(726/3,5,9,10) + Keywords - See search history printout	11/13/2007	YP
(705/64,65,66,67,68,69,50,51) + Keywords- See search history printout	11/13/2007	YP
(380/277,278,279) + Keywords - See seach history printout	11/13/2007	YP
Other keyword searches in East - See search history printout	11/13/2007	YP
Consulted with Thanhnga Truong	11/14/2007	YP

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
713	155,156	11/13/2007	YP